

New ITO Supplier Qualification Results

Roy Chancellor

ITO Qualification Results

- Background and Motivation
- Qualification test
 - Green Ys
 - Test procedure
- Analysis and Results
- Conclusions and Recommendations

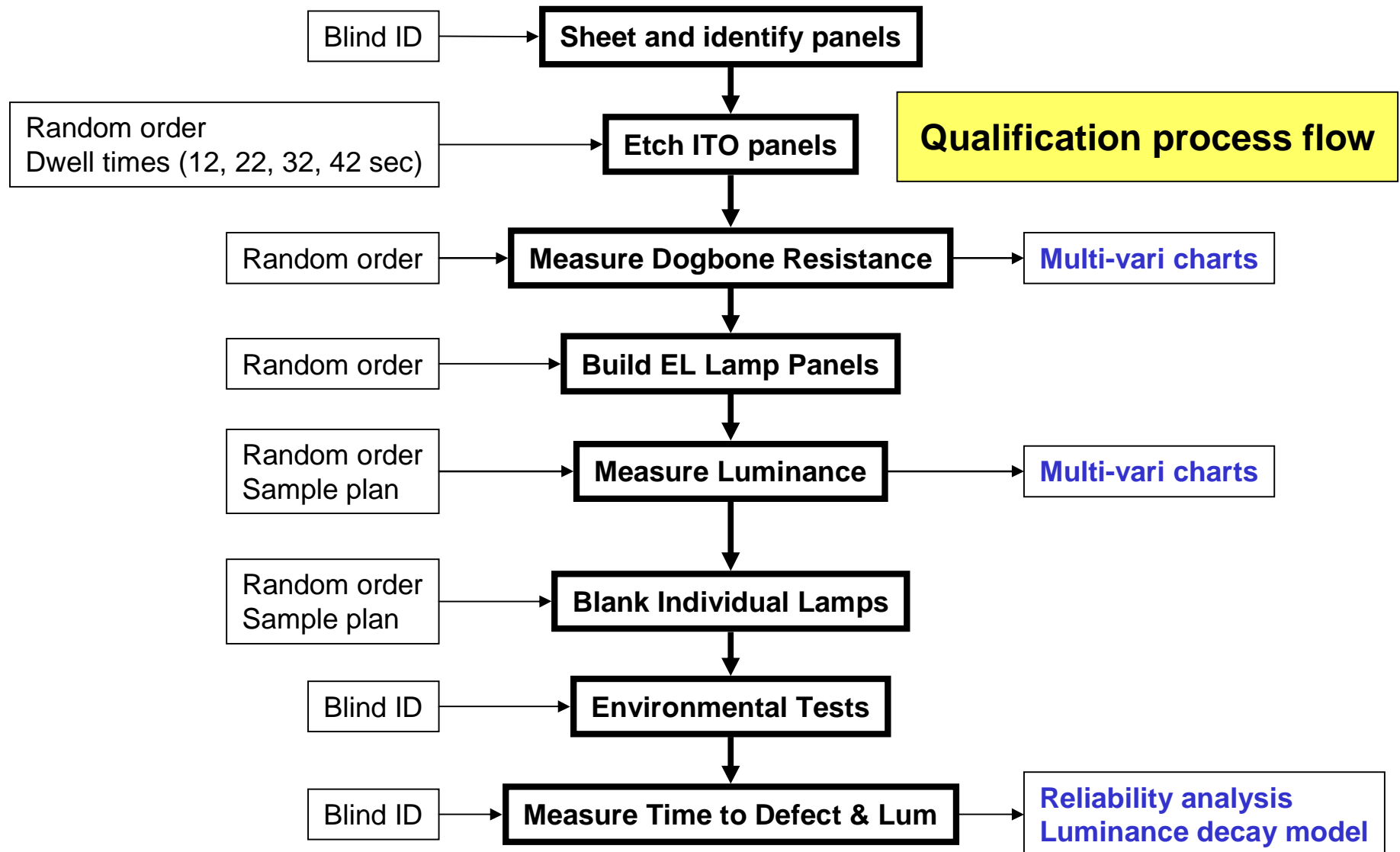
ITO Qualification Results

- Background and Motivation
 - Solidify ITO supply chain by qualifying a second source (equivalent to existing)
 - Previous attempts to qualify ### material were hampered by
 - Material problems (ITO formulation; oxygen level)
 - Test uncertainties
 - Objective
 - Perform a statistically designed reliability test that compares Supplier A to Supplier B (current standard)

ITO Qualification Results

- Qualification test
 - Green YS (Green = color of money)
 - Sheet resistivity (Ω / square)
 - Dogbone resistance ($k\Omega$)
 - Lamp luminance @ $t=0$ (fL)
 - Lamp luminance decay in high temp / high humidity environment
 - Time to formation of defects in HT/HH environment
 - Test procedure
 - Emphasis on **blindness** to ensure impartiality
 - **Randomization** to avoid time-related biases

ITO Qualification Results



ITO Qualification Results

- Test materials
 - Three lots of Standard chosen at random
 - Five lots of NEW
 - Two production lots from machine NV1
 - Three lots with different b^* value from NV2
- Panels sampled from the beginning, middle, and end of the rolls

Blind ID	Supplier	Lot #	Common ID
300		NV1-1787-A3	NV1-A3
764		NV1-1787-A1	NV1-A1
113		NV2-344-A2	$b^* = 3.0$
699		NV2-344-A3	$b^* = 0.0$
469		NV2-344-A1	$b^* = 1.0$
400		5310283-1D	283-1D
103		5310274-1L	274-1L
627		5310259-1G	259-1G

Panel ID	
1	Beginning of Roll (First 12')
2	
3	
4	
5	
6	
7	
8	

9	Middle of Roll (Middle 12')
10	
11	
12	
13	
14	
15	
16	

17	End of Roll (Last 12')
18	
19	
20	
21	
22	
23	
24	

ITO Qualification Results

- Analysis and Results
 - **Dogbone resistance**
 - Luminance at $t=0$
 - Time to defects (reliability)
 - Luminance decay

ITO Qualification Results

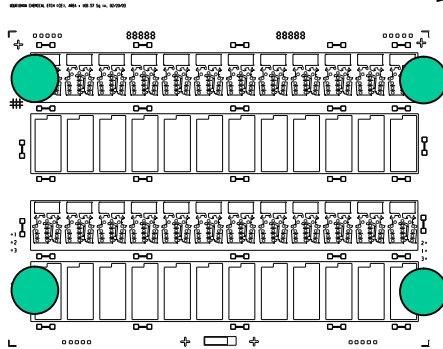
Green Y = Dogbone Resistance, k Ω (measure of Degree of Etch)

Variation Family

Notes

Orientation – Orientation
Same Side

Not measured

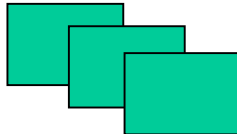


Side – Side
Same Row

Large contrast for NEW b* 1, 2, 3 material; small contrast on STD materials. Larger contrast for 32 sec than 22 sec dwell.

Row – Row
Same Panel

Medium contrast for 22 sec dwell; larger for 32 sec. Medium contrast for b* 1, 2, 3 material; small contrast for STD material



Panel – Panel
Same Web Location

Small contrast (large for b* 3 @ 32 sec)



Web Loc – Web Loc
Same ITO Type

Small contrast overall; medium contrast for b* 3 @ 32 sec. No leverage (non-random pattern)

NEW

STD

ITO Type – ITO type
Same Dwell Time

Small contrast for STD and NEW NV1 rolls; large contrast for b* rolls (by design); variation is much larger for b* 1, 2, 3 rolls

12 s

22 s

32 s

42 s

Dwell Time – Dwell Time

High contrast. Variation increases significantly with dwell for NEW b* 1, 2, 3 rolls; **22 sec is best dwell for both materials**

ITO Qualification Results

10UR184XA CHEMICAL ETCH (CE), AREA = 108.57 Sq in, 02/20/03

Left

Data collection plan for dogbone resistance

Right

Row 1

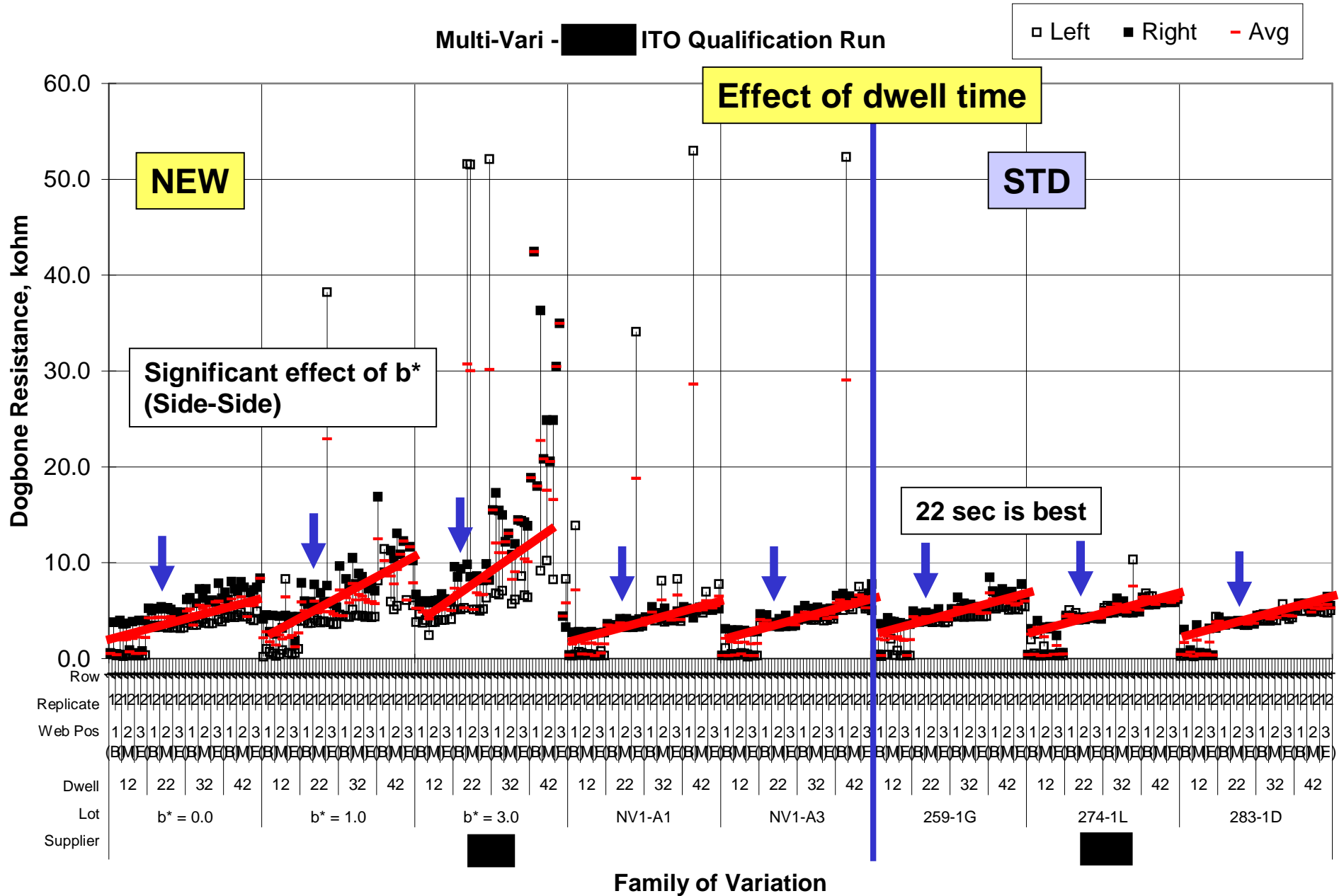
ITO Qualification Run Plan

ITO ID	Panel ID	Dwell Time, sec	Web Loc	Panel Rep	Row	Dogbone, kohm		Run Order	Unique	Group
						Left	Right			
699	22	32	3 (E)	2	1			48	15378	4
699	22	32	3 (E)	2	4			48	15378	4
103	13	32	2 (M)	1	1			47	1339	4
103	13	32	2 (M)	1	4			47	1339	4
469	13	32	2 (M)	1	1			46	6097	4
469	13	32	2 (M)	1	4			46	6097	4
103	14	32	2 (M)	2	1			45	1442	4
103	14	32	2 (M)	2	4			45	1442	4
400	6	32	1 (B)	2	1			45	2400	4

Row 4

5/29/2003

ITO Qualification Results



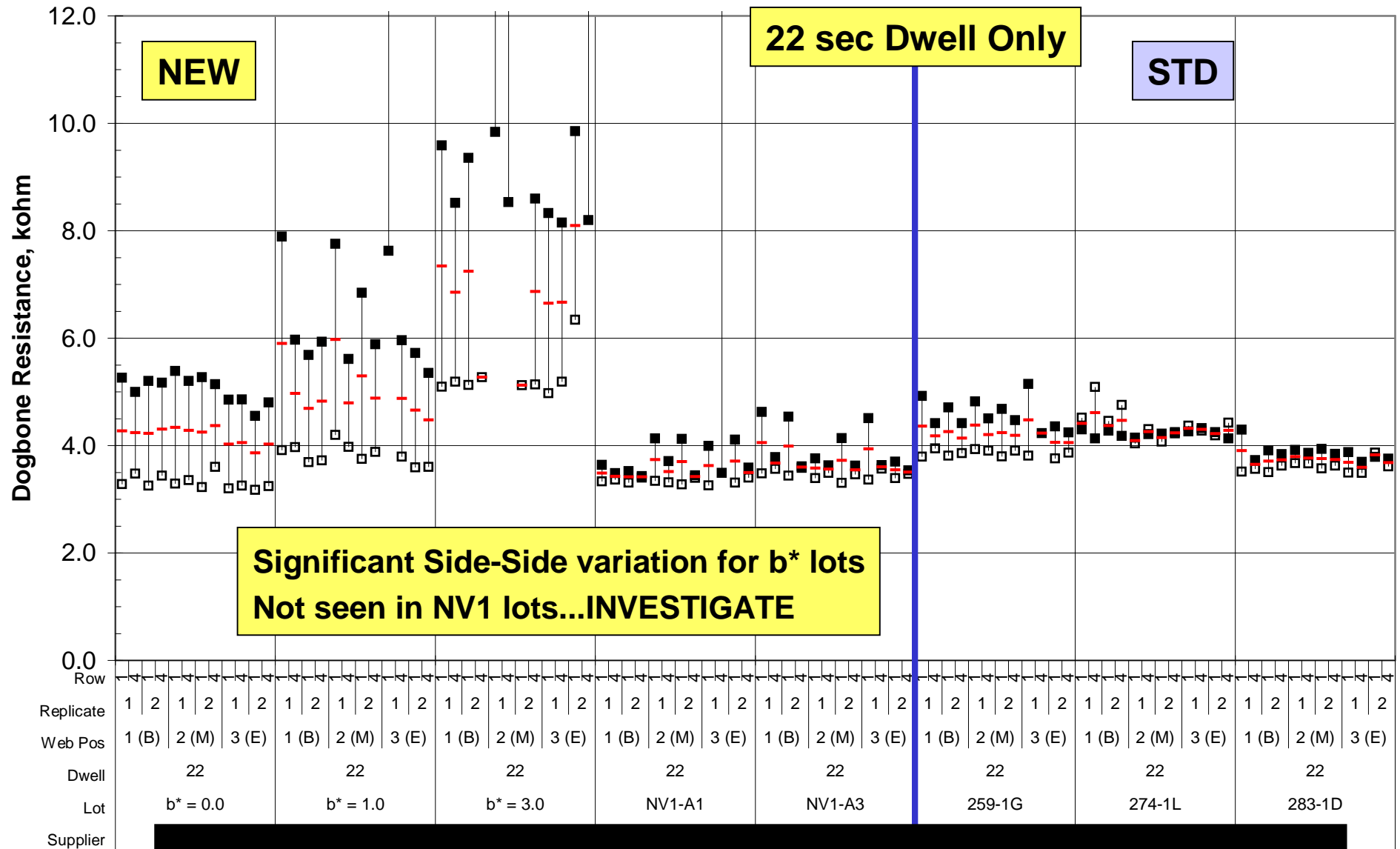
ITO Qualification Results

- Dogbone resistance
 - Dwell time of 22 seconds is the “best”
 - ITO is fully etched
 - No evidence of over-etched edges
 - Achieved easily in production
 - b* lots had more side-side variation
 - Made on NV2 -> is this significant?
 - 52” roll cut into two 24” rolls
 - Resistance of NV1 rolls is consistent and equivalent to the three STD rolls
- Look at panels etched at 22 seconds for more detail...

ITO Qualification Results

Multi-Vari - XXXXXXXXXX ITO Qualification Run

□ Left ■ Right - Avg



ITO Qualification Results

- Analysis and Results
 - Dogbone resistance
 - **Luminance at $t=0$**
 - Time to defects (reliability)
 - Luminance decay

ITO Qualification Results

Green Y = Luminance @ $t = 0$, fL

Variation Family

Notes

~~Orientation – Orientation
Same Side~~

Not measured

Side – Side
Same Row

Medium contrast (not ITO related).

Row – Row
Same Panel

Low contrast.

~~Panel – Panel
Same Web Location~~

Not measured

~~Web Loc – Web Loc
Same ITO Type~~

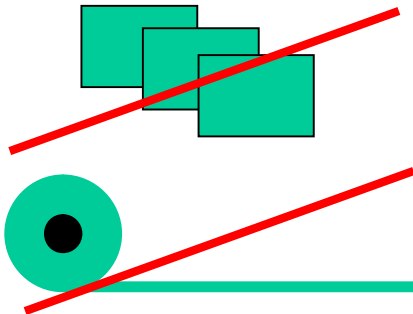
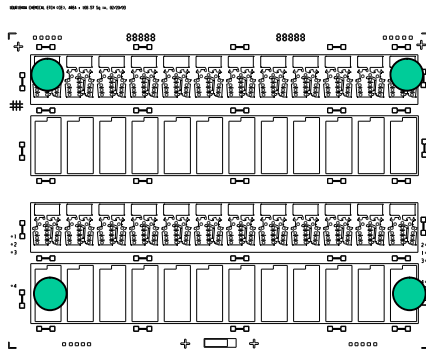
Not measured

ITO Type – ITO type
Same Dwell Time

Low contrast.

Dwell Time – Dwell Time

Low contrast.



NEW

STD

12 s

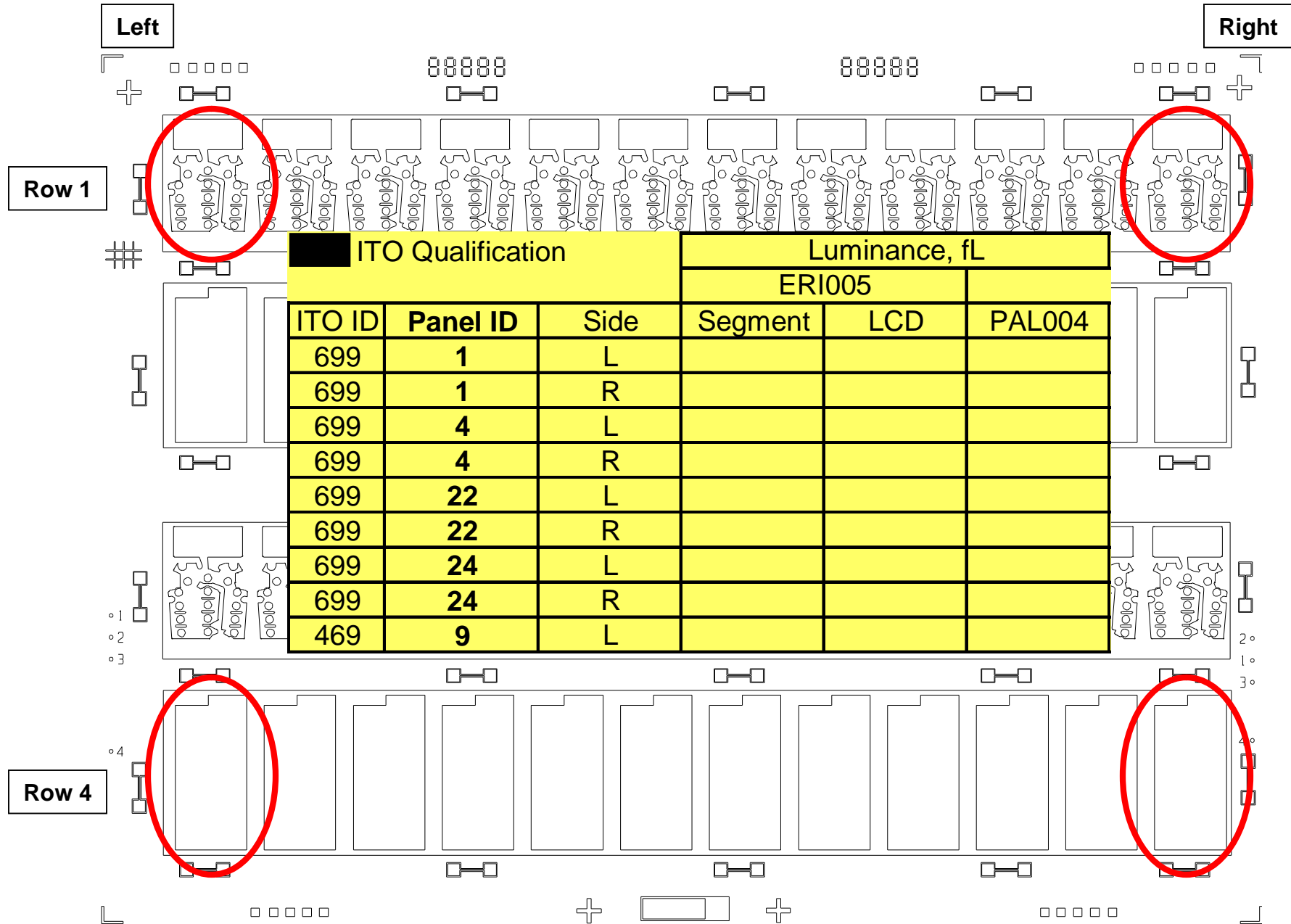
22 s

32 s

42 s

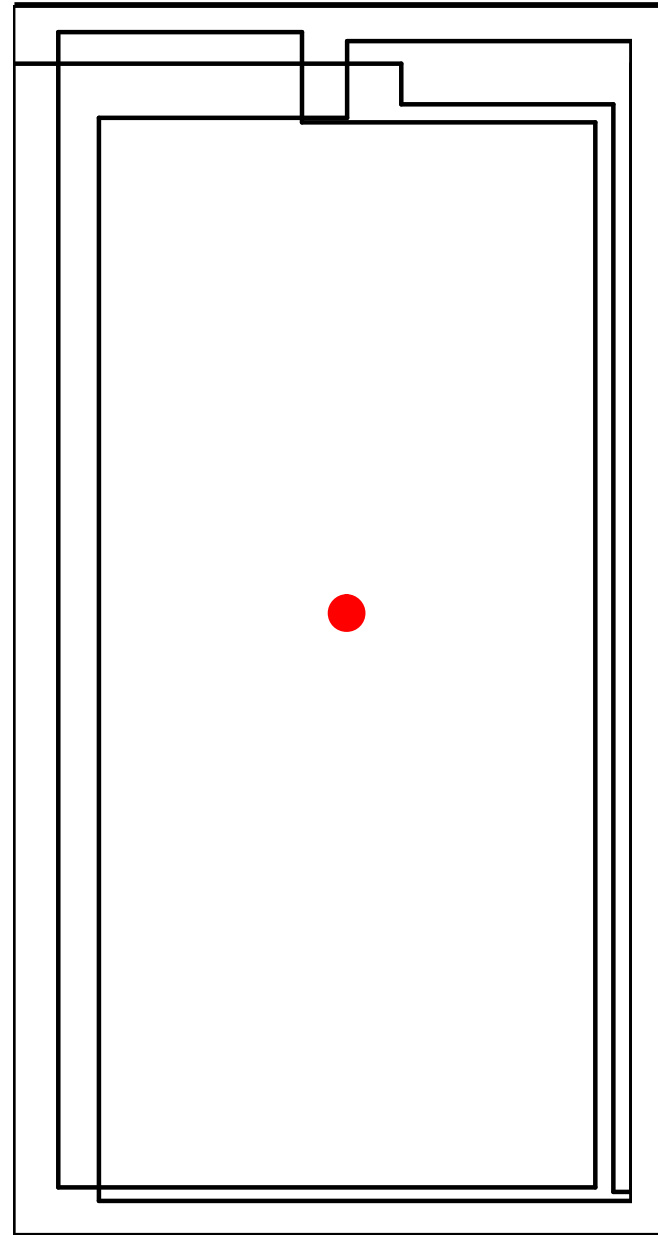
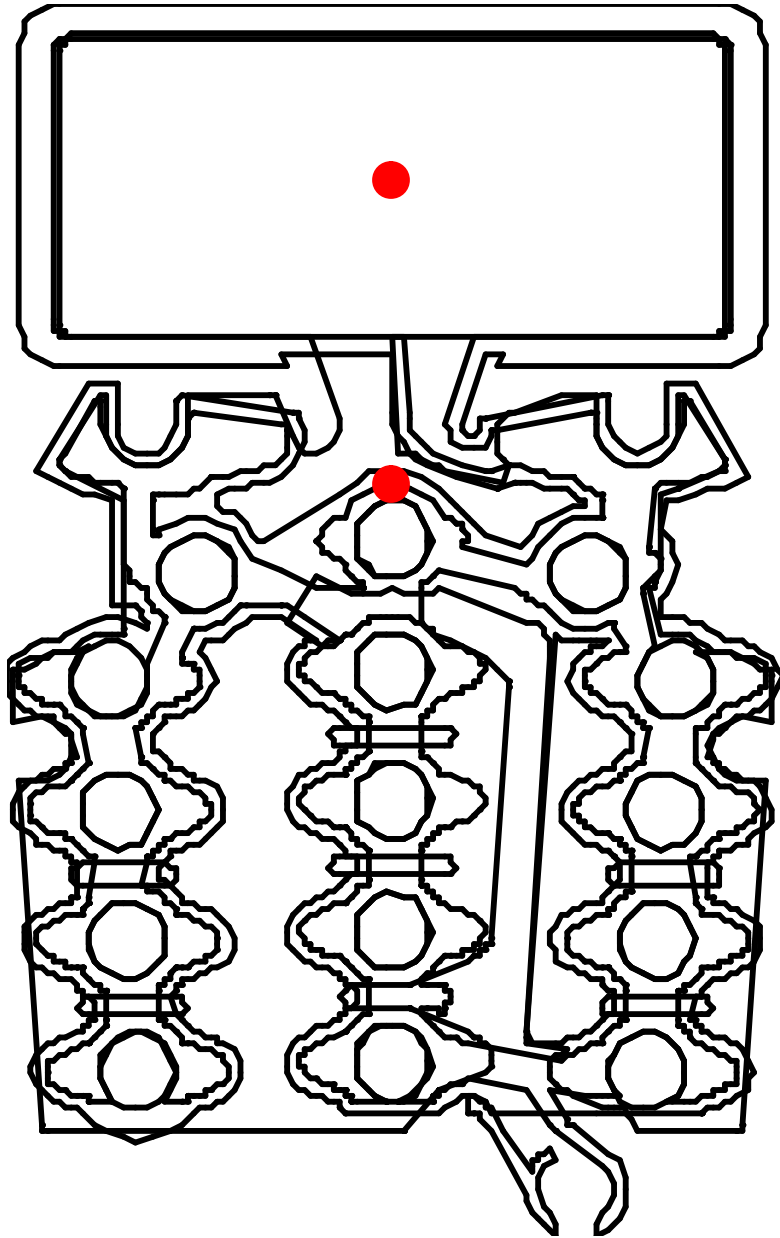
ITO Qualification Plan: Luminance Measurement Plan

10UR184XA CHEMICAL ETCH (CE), AREA = 108.57 Sq in, 02/20/03



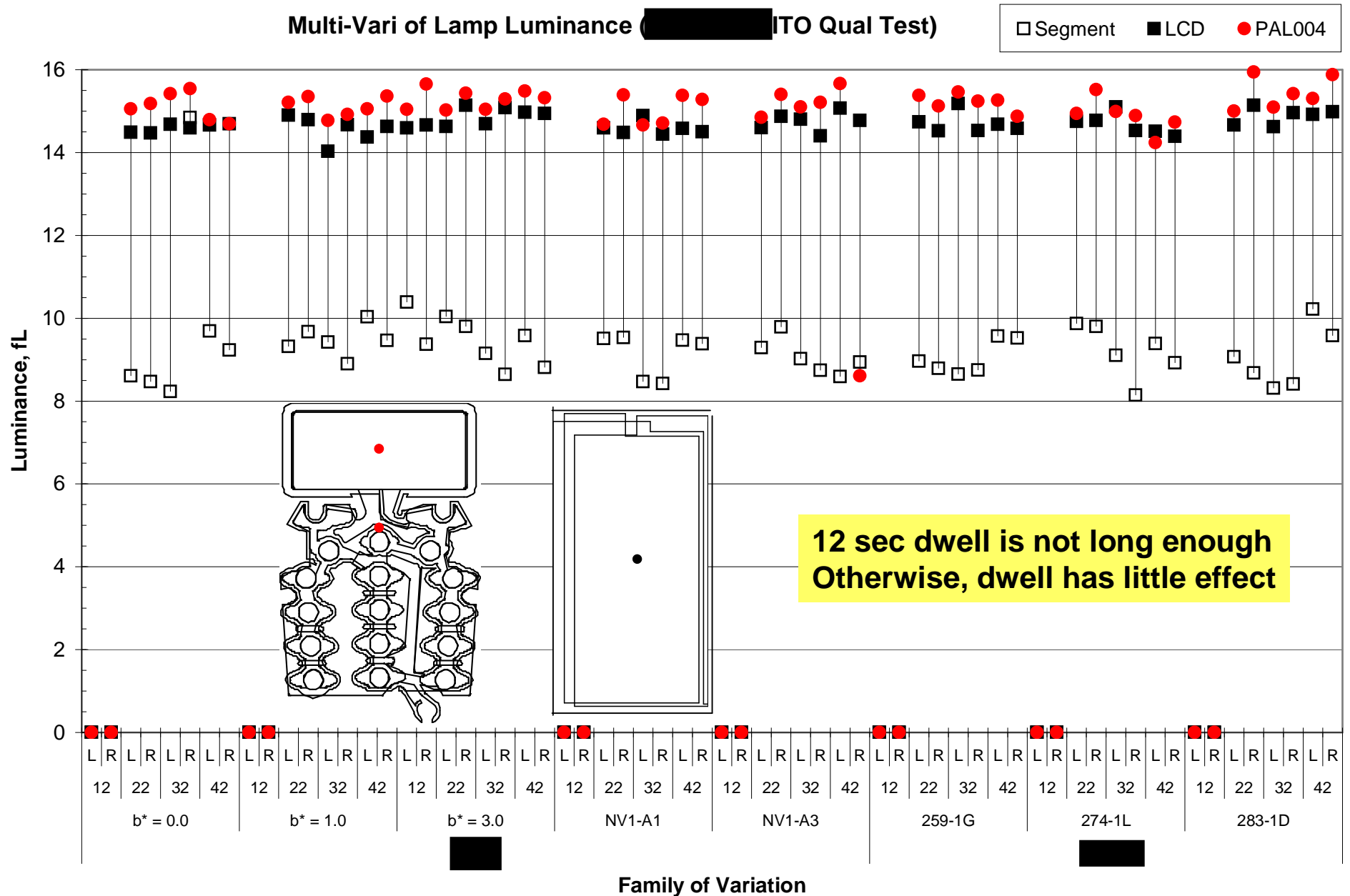
5/29/2003

ITO Qualification Plan: Luminance Measurement Plan



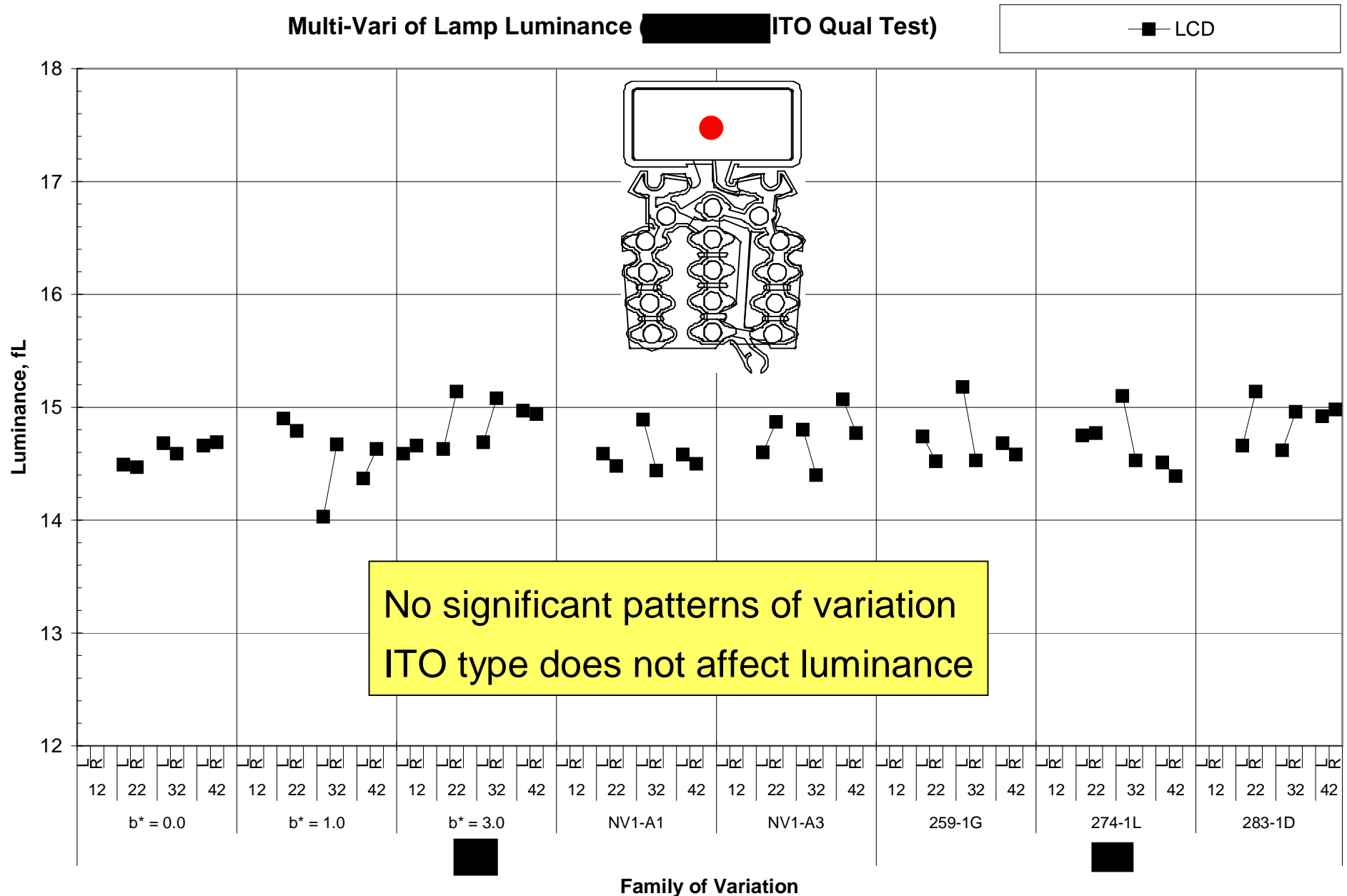
ITO Qualification Results

Multi-Vari of Lamp Luminance ([REDACTED] ITO Qual Test)



ITO Qualification Results

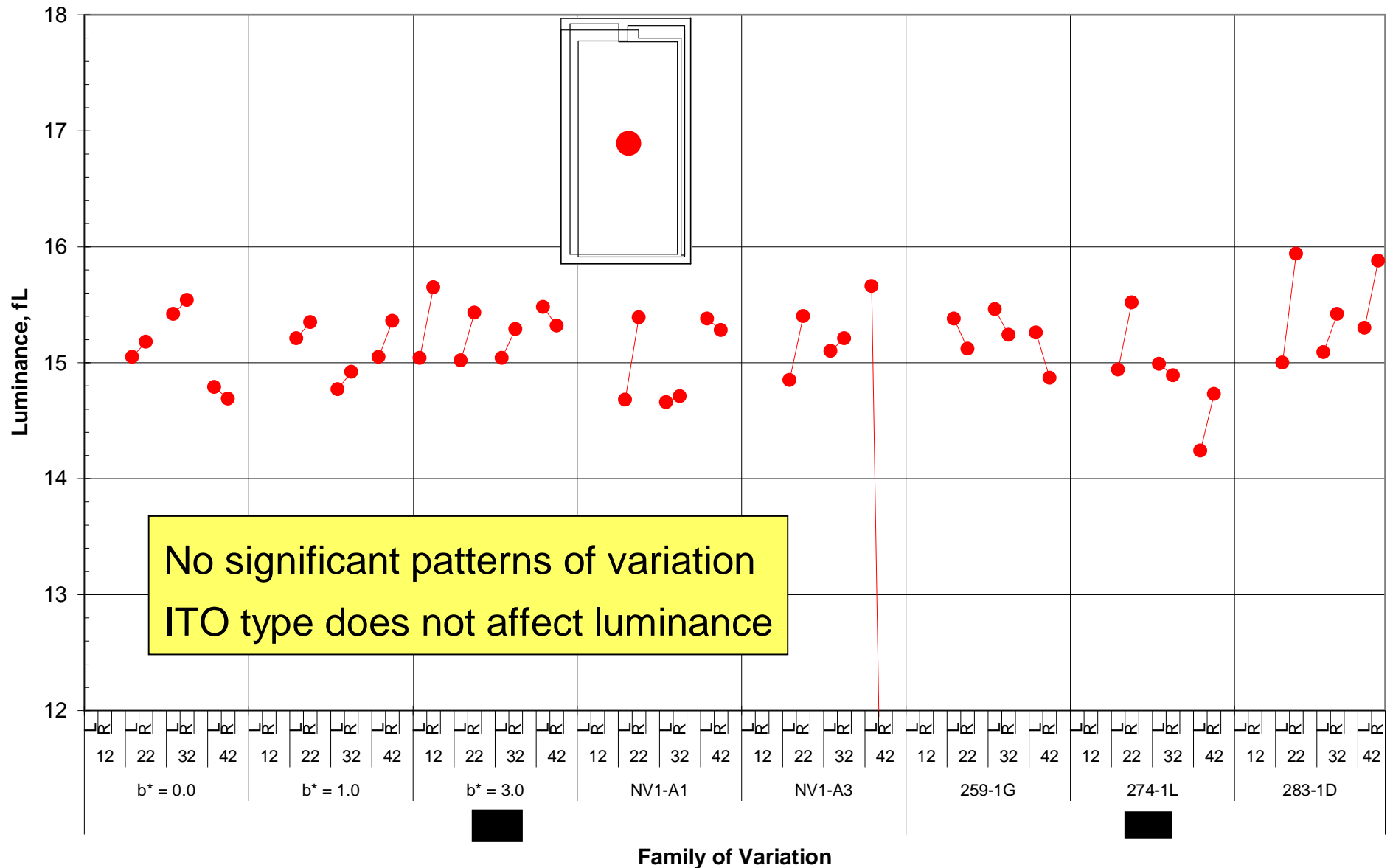
Multi-Vari of Lamp Luminance (ITO Qual Test)



ITO Qualification Results

Multi-Vari of Lamp Luminance ([REDACTED] ITO Qual Test)

—●— PAL004



ITO Qualification Results

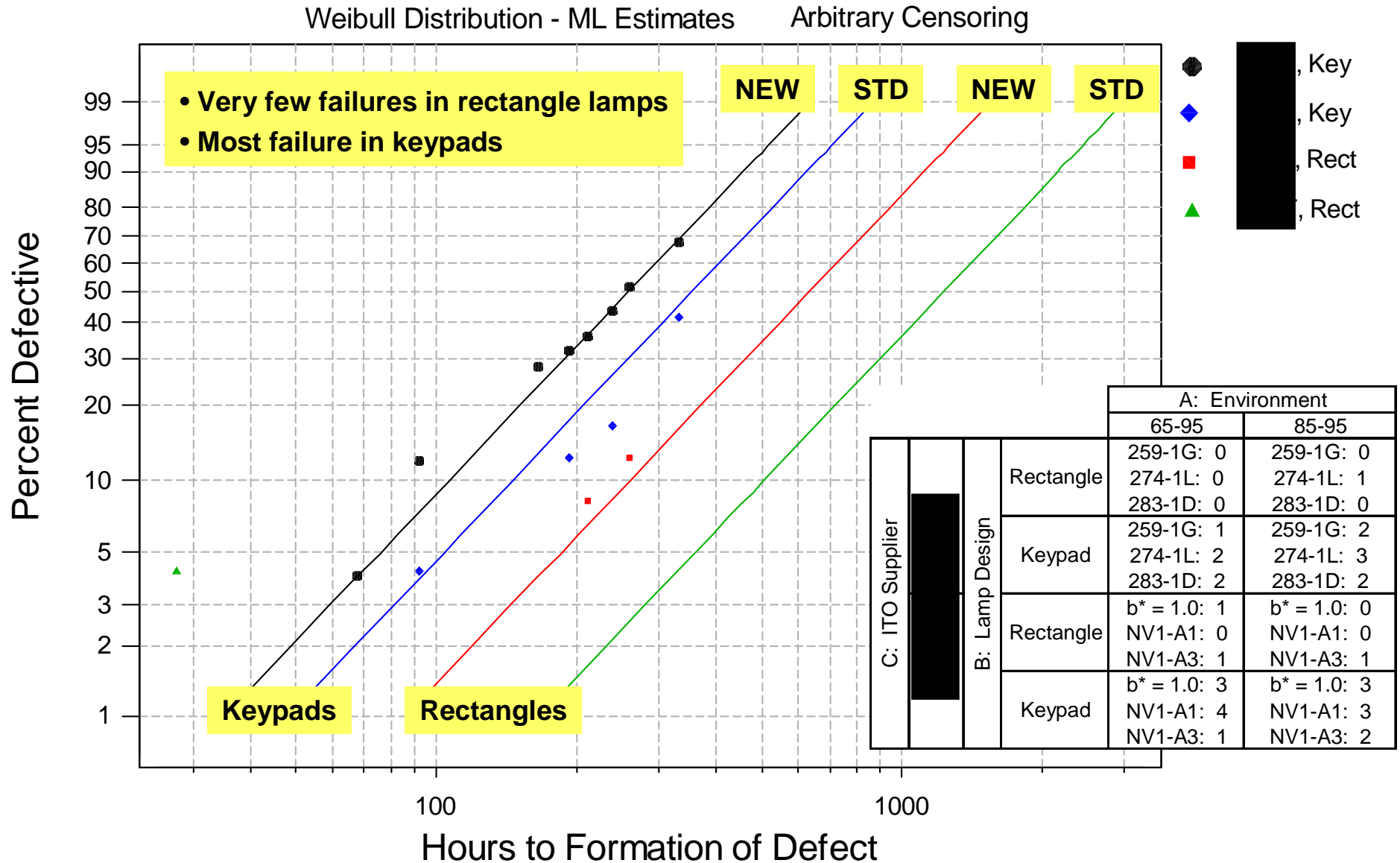
- Analysis and Results
 - Dogbone resistance
 - Luminance at $t=0$
 - **Time to defects (reliability)**
 - Luminance decay

ITO Qualification Results

- Sampling plan
 - Select lamps with 22 sec dwell only
 - NEW: b* 1.0, NV1-A1, NV1-A3 (b* 0 and b* 3 were **NOT** tested)
 - STD: all three lots
 - Random panel selection (web position and panel replicate)
 - Four lamps per panel (one per quadrant)
- Test conditions
 - 65 C / 95% RH
 - 85 C / 95% RH
 - 100% duty cycle, 80 V, 200 Hz
- Measurements
 - Luminance (decay)
 - Cosmetic defects (black spots)
 - Pictures with digital camera
 - Time it first occurred
- Measurement frequency
 - Luminance: per standard protocol
 - Cosmetics: once per 24 hour period
- Total test time
 - 65-95: 380 hours
 - 85-95: 330 hours

ITO Qualification Results

Probability Plot for Time to Defective



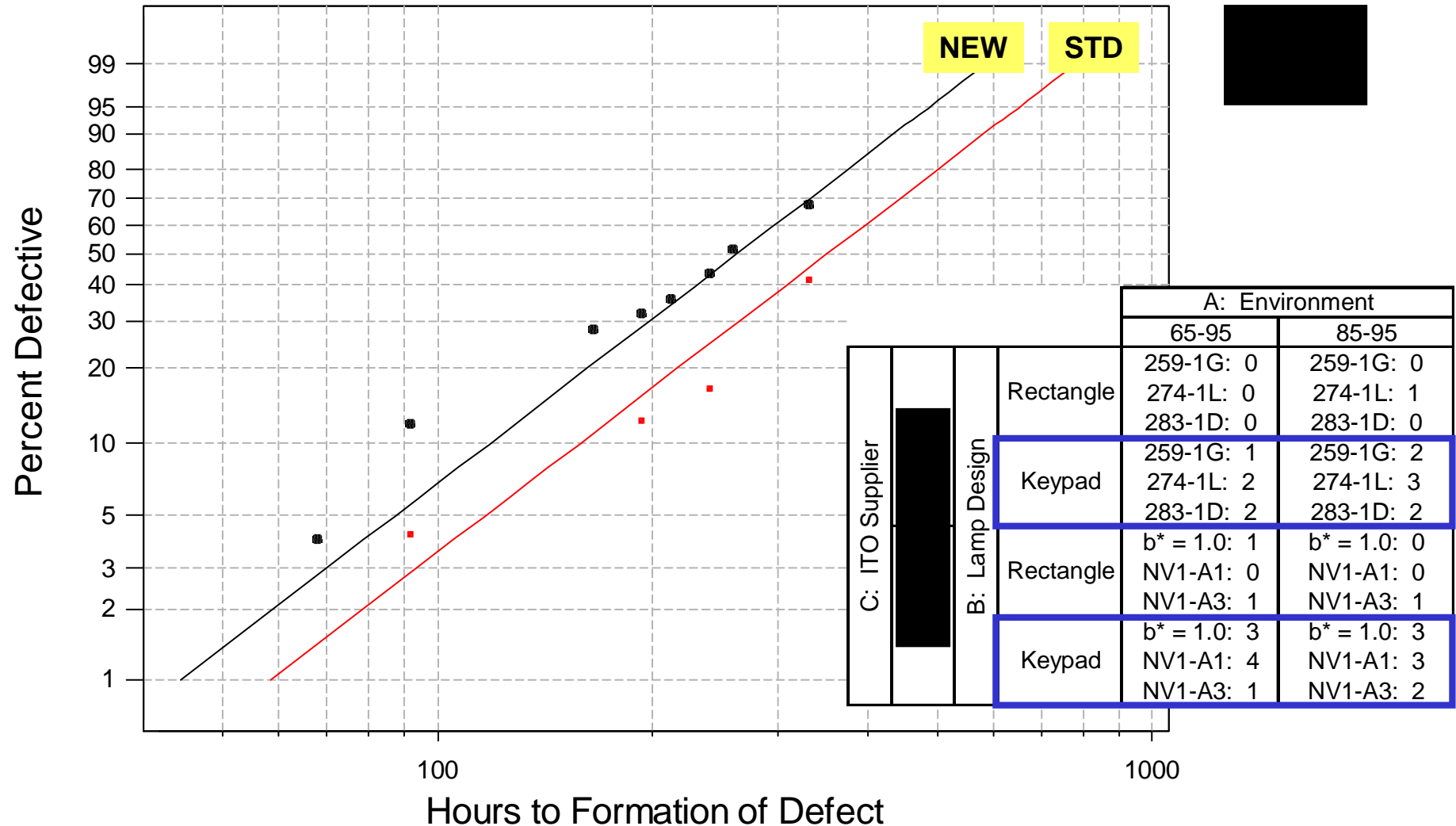
ITO Qualification Results

Probability Plot for Time to Defective

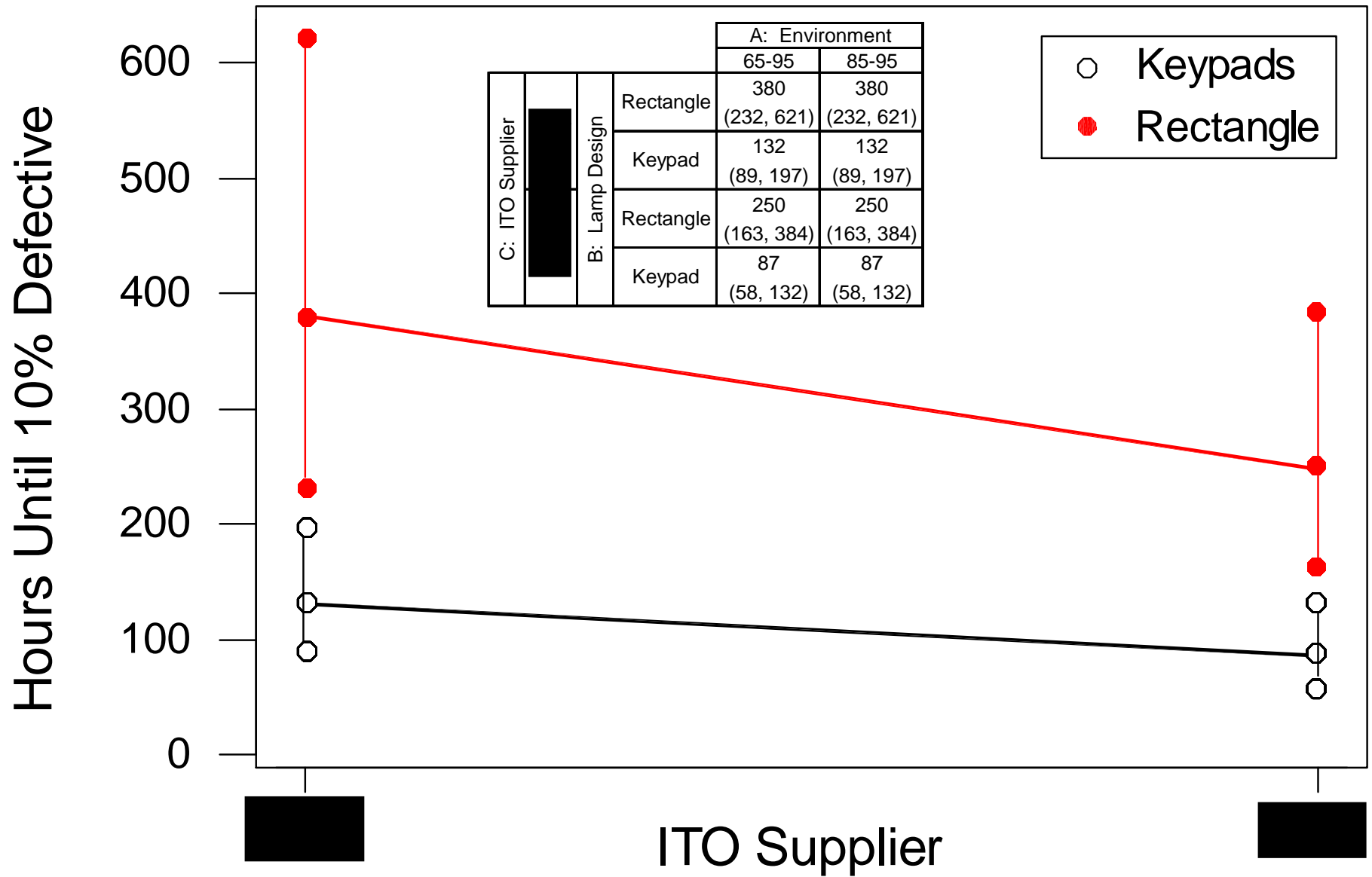
Weibull Distribution - ML Estimates

Arbitrary Censoring

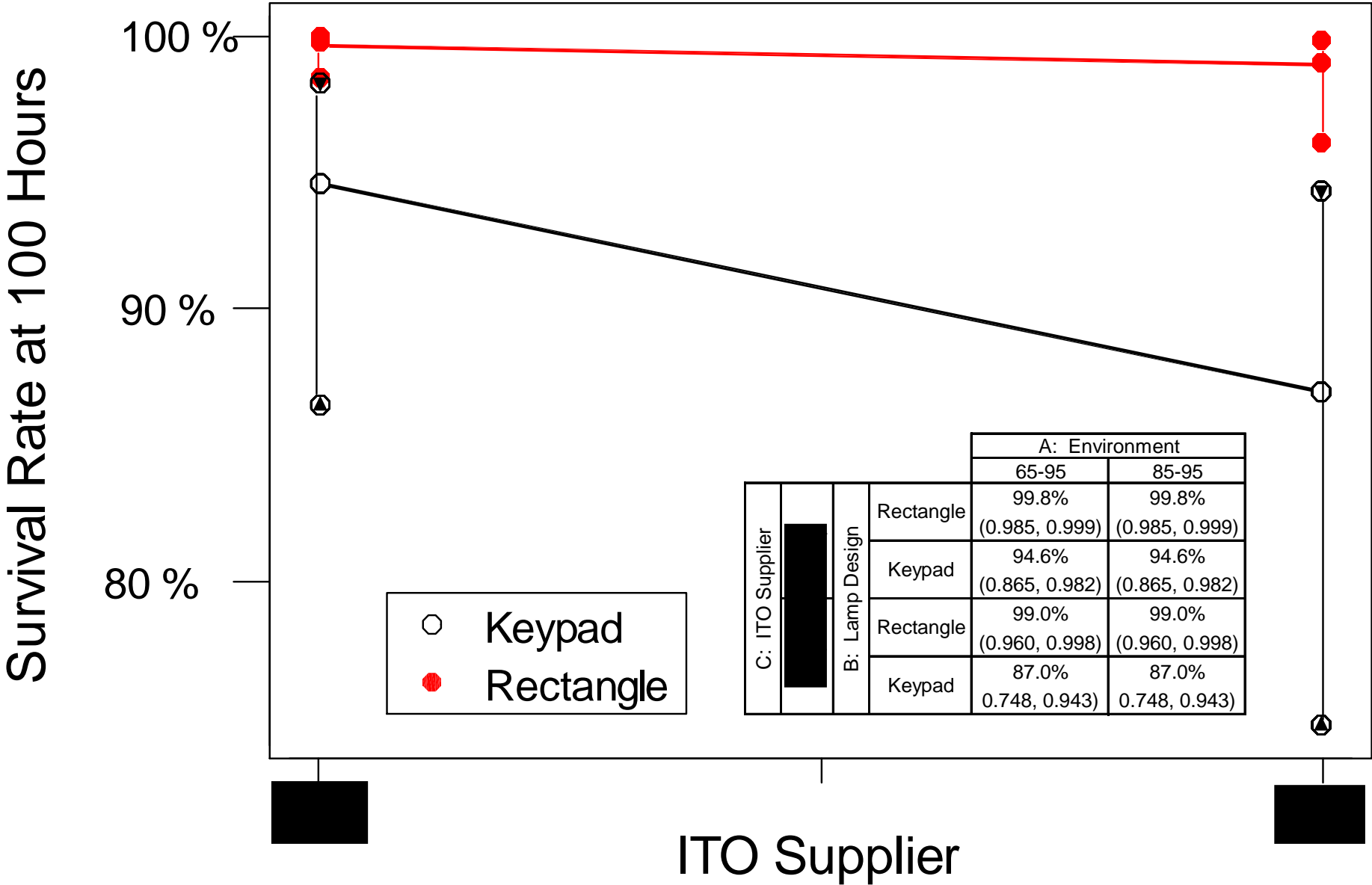
*** Keypads ***



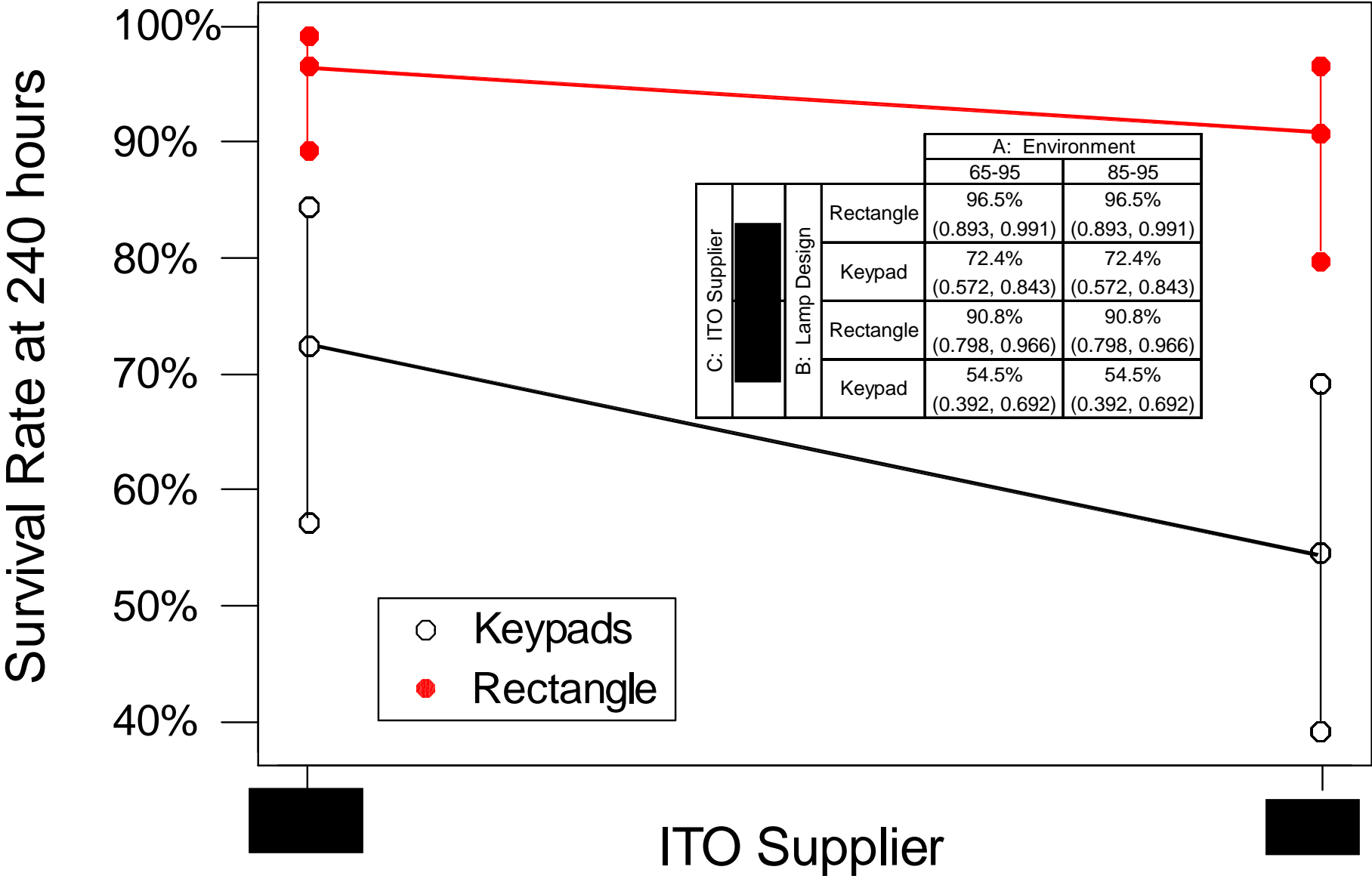
ITO Qualification Results



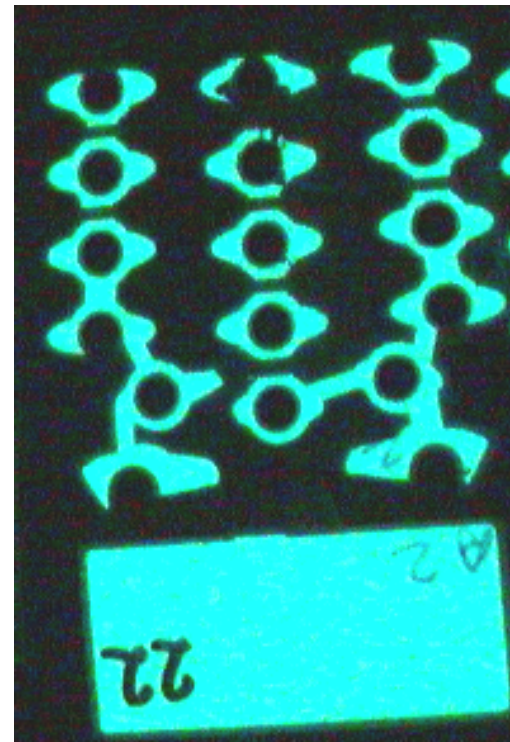
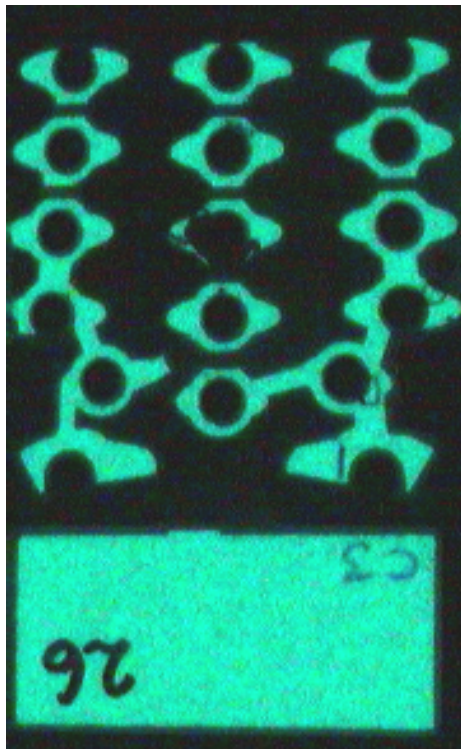
ITO Qualification Results



ITO Qualification Results



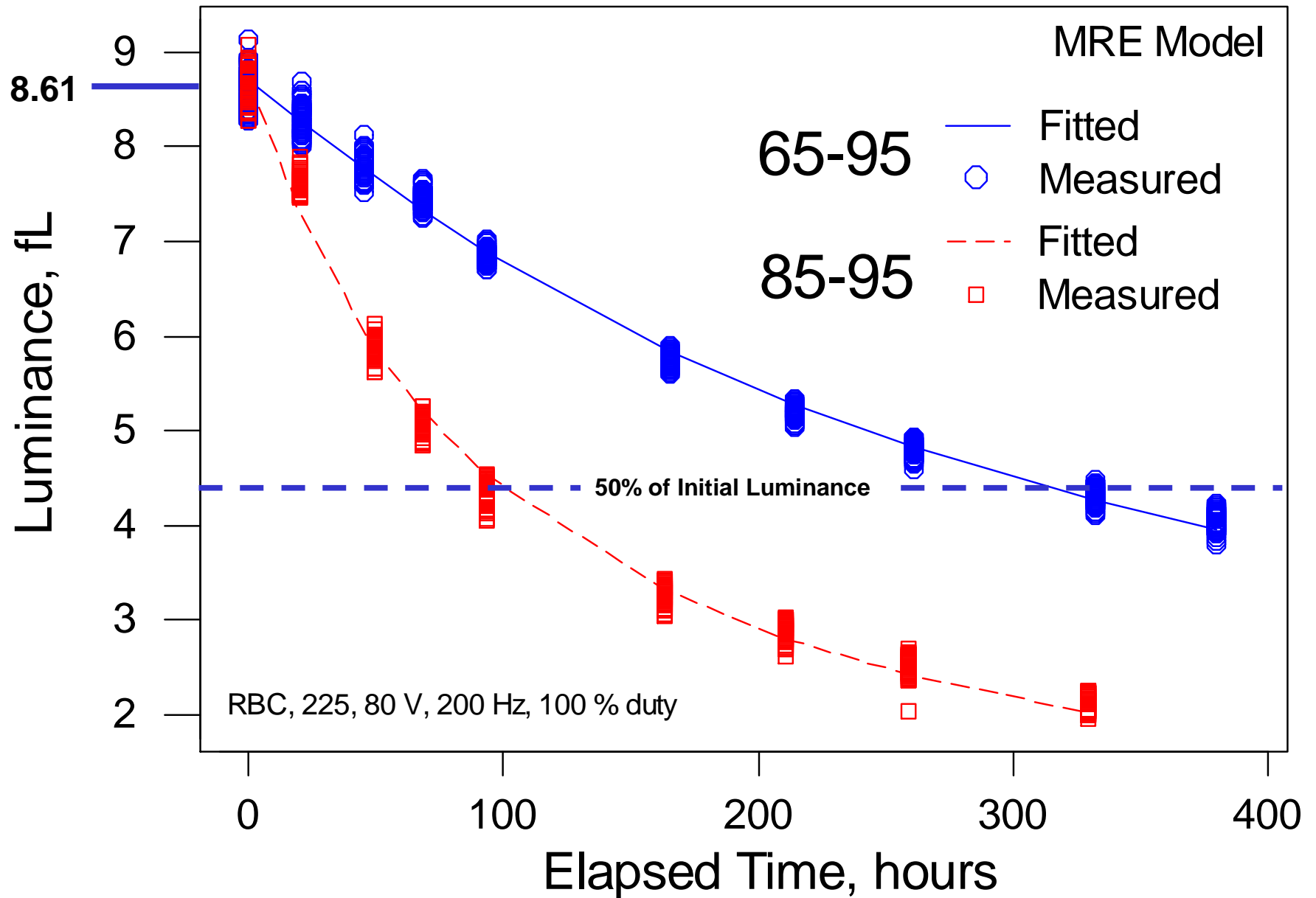
Examples of Defects (Unlit Keypad Segments)



ITO Qualification Results

- Analysis and Results
 - Dogbone resistance
 - Luminance at $t=0$
 - Time to defects (reliability)
 - **Luminance decay**

ITO Qualification Results



ITO Qualification Results

$$Lum = \frac{L_0}{(1 + \beta \cdot t^\gamma)}$$

$$Lum = \frac{(L_0 + \lambda_E E + \lambda_D D + \lambda_S S)}{\left[1 + (\beta_0 + \beta_E E + \beta_D D + \beta_S S) \cdot t^{\gamma_0 + \gamma_E E + \gamma_D D + \gamma_S S}\right]}$$

Coefficient Estimates								
Coeff	Est	Diff	Coeff	Est	Diff	Coeff	Est	Diff
λ_0	8.707		β_0	0.00198		γ_0	1.079	
λ_{Env}	0.0869	1.00%	β_{Env}	0.0073	370.8%	γ_{Env}	-0.066	-6.1%
λ_{Des}	-0.0816	-0.94%	β_{Des}	-0.0000295	-1.49%	γ_{Des}	0.001729	0.16%
λ_{Sup}	0.0093	0.11%	β_{Sup}	0.0000545	2.75%	γ_{Sup}	-0.00482	-0.45%

- Only the environment affects luminance decay
- Design and supplier effects are not significant

ITO Qualification Results

- Background and Motivation
- Qualification test
 - Green Ys
 - Test procedure
- Analysis and Results
- **Conclusions and Recommendations**

ITO Qualification Results

- **Etchability**

- Variation in sheet resistivity in three b^* lots
 - NV1 lots are quite consistent
 - NV2 lots had more side-side variation in dogbone resistance
- Resistance of $b^* 3.0$ lot is too high
 - Does not have a significant impact on luminance; not tested in environments
- b^* between 0 and 1 is good (maybe -0.5 to 2.0 is acceptable range)

- **Luminance**

- No significant difference between suppliers (all lots tested)

- **Defects in environments**

- Significant practical difference in time to defects due to **lamp design**
 - Keypad design performed worse than rectangle design
- Statistical difference due to **supplier**
 - ITO has lower time to formation of defects
 - **Practical difference is difficult to determine** (e.g. how does environmental performance translate to field performance?)
 - How would $b^* 0$ perform?

- **Recommendations**

- Conditional approval of NEW material
 - Non-automotive applications until additional testing is performed
- Specification for b^* needs to be finalized and control plan implemented